

4/17/2013



**RELIABILITY MONITOR REPORT  
FOR**

**MFN Standard Metal Gate CMOS (M6)**

**MAXIM INTEGRATED**

**160 RIO ROBLES  
SAN JOSE, CA 95134**

**This Report was prepared by  
MAXIM INTEGRATED Reliability Engineering**

**Summary:**

The data in the tables that follow was generated as the result of an on-going Process Reliability Monitor. The specific products in this process monitor are:

MAX232MJE/88
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The calculated failure rate for devices using this process is:

**FAILURE RATE: MTTF (YRS): 17440 QUANTITY: 90 FAILS: 0 FITS: 6.5**

The parameters used to calculate this failure rate are as follows:

**Cf: 60% Ea: 0.7 Tu: 25 °C**

The reliability data follows and in this section is the detailed reliability data by stress. The reliability data section includes the latest data available. This report covers data between 4/1/2012 and 3/31/2013 .

**Process Information:**

Process Description: MFN Standard Metal Gate CMOS (M6)

**OPERATING LIFE**

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT	QUANTITY	FAILS	LOT NO.
HIGH TEMP OP LIFE	1142	MAX232MJE/883B	135°C	1000 HRS	45	0	NPWBKD018Q3
HIGH TEMP OP LIFE	1143	MAX232MJE/883B	135°C	1000 HRS	45	0	NPWBKD018Q2
<b>Total:</b>						<b>0</b>	

**STORAGE LIFE**

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT	QUANTITY	FAILS	LOT NO.
STORAGE LIFE	1143	MAX232MJE/883B	150°C	1000 HRS	77	0	NPWBKD018Q1
STORAGE LIFE	1143	MAX232MJE/883B	150°C	1000 HRS	77	0	NPWBKD018Q2
STORAGE LIFE	1143	MAX232MJE/883B	150°C	1000 HRS	77	0	NPWBKD018Q3
<b>Total:</b>						<b>0</b>	

**TEMPERATURE CYCLE**

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT	QUANTITY	FAILS	LOT NO.
TEMP CYCLE, 5' RAMP, 10' DWELL	1143	MAX232MJE/883B	-65C TO 150C	1000 CYS	77	0	NPWBKD018Q1
TEMP CYCLE, 5' RAMP, 10' DWELL	1143	MAX232MJE/883B	-65C TO 150C	1000 CYS	77	0	NPWBKD018Q2
TEMP CYCLE, 5' RAMP, 10' DWELL	1143	MAX232MJE/883B	-65C TO 150C	1000 CYS	77	0	NPWBKD018Q3
<b>Total:</b>						<b>0</b>	

**FAILURE RATE: MTTF (YRS): 17440 QUANTITY: 90 FAILS: 0 FITS: 6.5**